

# **650V GaN Power Transistor (FET)**

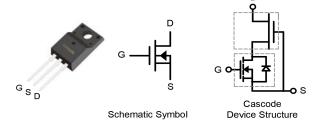
#### **Features**

- Easy to use, compatible with standard gate drivers
- Excellent Q<sub>G</sub> x R<sub>DS(on)</sub> figure of merit (FOM)
- Low  $Q_{RR}$ , no free-wheeling diode required
- Low switching loss
- RoHS compliant and Halogen-free

Product Summary			
$V_{DSS}$	650	V	
R <sub>DS(on), typ</sub>	240	mΩ	
Q <sub>G, typ</sub>	21	nC	
Q <sub>RR, typ</sub>	39	nC	

# **Applications**

- High efficiency power supplies
- Telecom and datacom
- Automotive
- Servo motors



# **Packaging**

Part Number	Package	Packaging	Base QTY
RX65T300FS2A	3 Lead TO-220F	Tube	50

#### Maximum ratings, at T<sub>C</sub>=25 °C, unless otherwise specified

Symbol	Parameter	Limit Value	Unit	
	Continuous drain current @T <sub>C</sub> =25°C	7.3	Α	
I <sub>D</sub>	Continuous drain current @T <sub>C</sub> =100°C	4.7	Α	
	Pulsed drain current @T <sub>C</sub> =25°C (pulse	e width: 10us)	40	Α
I <sub>DM</sub>	Pulsed drain current @T <sub>C</sub> =150°C (pul	26	Α	
V <sub>DSS</sub>	Drain to source voltage (T <sub>J</sub> = -55°C to	650	V	
V <sub>TDSS</sub>	Transient drain to source voltage <sup>a</sup>	800	V	
$V_{GSS}$	Gate to source voltage	±20	V	
$P_D$	Maximum power dissipation @T <sub>C</sub> =25°C		24	W
T <sub>C</sub>	On a vating to war a vature	Case	-55 to 150	°C
T <sub>J</sub>	Operating temperature	Junction	-55 to 150	°C
T <sub>S</sub>	Storage temperature	-55 to 150	°C	
T <sub>CSOLD</sub>	Soldering peak temperature		260	°C



#### **Thermal Resistance**

Symbol	Parameter	Typical	Unit
Rөлс	Junction-to-case	5.2	°C/W
Roja	Junction-to-ambient <sup>b</sup>	50	°C/W

#### Notes:

- a. Off-state spike duty cycle < 0.01, spike duration < 2us
- Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm<sup>2</sup> copper area and 70μm thickness)



## Electrical Parameters, at T<sub>J</sub>=25 °C, unless otherwise specified

Symbol	Min	Тур	Max	Unit	Test Conditions
Forward Charac	cteristics			I	
$V_{DSS\text{-MAX}}$	650	-	-	V	V <sub>GS</sub> =0V
$BV_Dss$		1000			V <sub>GS</sub> =0V, I <sub>DSS</sub> =250μA
$V_{GS(th)}$	1.1	1.8	2.5	V	$V_{DS}$ = $V_{GS}$ , $I_D$ = $500\mu A$
<b>5</b> (	-	240	300	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =25°C
$R_{DS(on)}^{c}$	-	500	-	11122	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =150°C
I	-	8	20	μΑ	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C
I <sub>DSS</sub>	-	50	-	μΑ	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C
1	-	-	150	nA	V <sub>GS</sub> =20V
$I_{GSS}$	-	-	-150	nA	V <sub>GS</sub> =-20V
C <sub>ISS</sub>	-	500	-	pF	
C <sub>oss</sub>	-	18	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =650V, f=1MHz
$C_{RSS}$	-	2	-	pF	
C <sub>O(er)</sub>	-	25	-	pF	
C <sub>O(tr)</sub>	-	45	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 - 650V
$Q_{G}$	-	21	-		
$Q_{GS}$	-	3	-	nC	V <sub>DS</sub> =400V, V <sub>GS</sub> =0 - 12V, I <sub>D</sub> =5.5A
$Q_{GD}$	-	3.5	-		
t <sub>D(on)</sub>	-	20	-		
t <sub>R</sub>	-	7	-		V 400V V 0 43V L 3A B 300
t <sub>D(off)</sub>	-	80	-	ns	$V_{DS}$ =400V, $V_{GS}$ =0 - 12V, $I_{D}$ =3A, $R_{G}$ =30 $\Omega$
t <sub>F</sub>	-	6	-		
Reverse Charac	teristics				
	-	1.2	-		V <sub>GS</sub> =0V, I <sub>S</sub> =2A, T <sub>J</sub> =25°C
$V_{SD}$	-	1.7	-	V	V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =25°C
	-	2	-		V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =150°C
t <sub>RR</sub>	-	12	-	ns	
$Q_{RR}$	-	39	-	nC	$I_S=3A$ , $V_{GS}=0V$ , $d_i/d_t=1000A/us$ , $V_{DD}=400V$

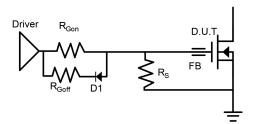
#### Notes:

c. Dynamic on-resistance; see Figure 17 and 18 for test circuit and configurations



#### **Circuit Implementation**

Mostly used in flyback, forward and push-pull converters



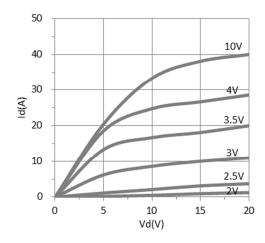
## **Recommended Single Ended Drive Circuit**

Recommended gate drive: (0 V, 12 V) with R<sub>Gon</sub> = 300 - 500  $\Omega$ , R<sub>Goff</sub> =10  $\Omega$ 

Gate	Gate	Gate	Gate Source	Gate
Ferrite Bead	Resistance	Resistance	Resistance	Diode
(FB)	(R <sub>Gon</sub> )	(R <sub>Goff</sub> )	(R <sub>s</sub> )	(D1)
300 - 600 Ω@100 MHz	300 - 500 $\Omega$	10 $\Omega$	10 kΩ	1N4148



#### Typical Characteristics, at T<sub>C</sub>=25 °C, unless otherwise specified

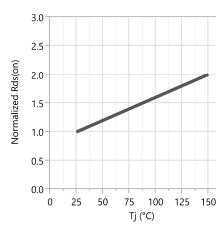


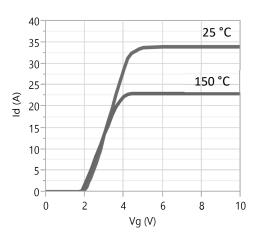
30 8V 20 3.5V ld(A) 3V 10 2.5V 2V 5 10 15 20 0 Vd(V)

Figure 1. Typical Output Characteristics T<sub>J</sub>=25°C



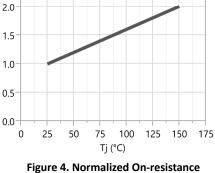
Figure 2. Typical Output Characteristics T<sub>J</sub>=150°C Parameter: V<sub>GS</sub>





**Figure 3. Typical Transfer Characteristics** 

V<sub>DS</sub>=10V, Parameter: T<sub>J</sub>



 $I_D=4A$ ,  $V_{GS}=8V$ 

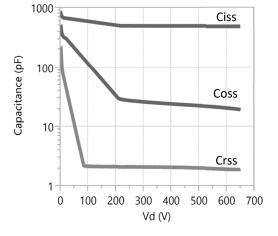


Figure 5. Typical Capacitance

V<sub>GS</sub>=0V, f=1MHZ

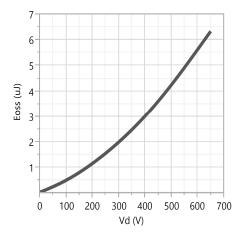


Figure 6. Typical Coss Stored Energy



## Typical Characteristics, at $T_C$ =25 °C, unless otherwise specified

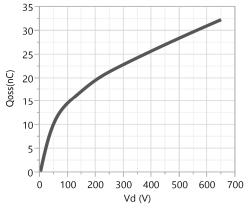


Figure 7. Typical Qoss

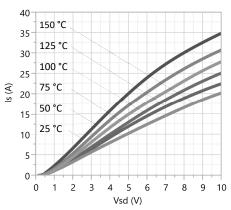


Figure 8. Forward Characteristic of Rev. Diode

Is=f(V<sub>S</sub>), Parameter T<sub>J</sub>

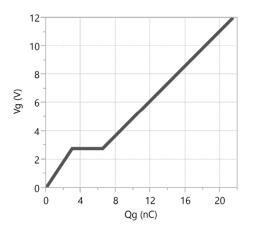


Figure 9. Typical Gate Charge

I<sub>DS</sub>=10A, V<sub>DS</sub>=400V

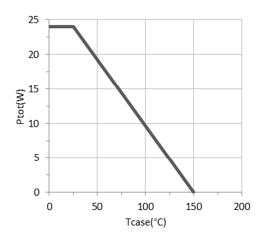


Figure 10. Power Dissipation

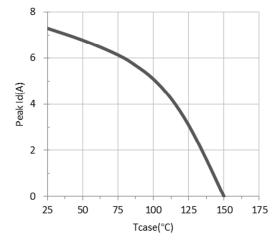


Figure 11. Current Derating

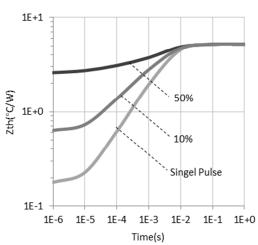
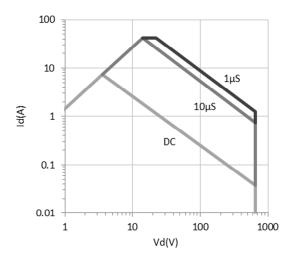


Figure 12. Transient Thermal Resistance





#### Typical Characteristics, at T<sub>C</sub>=25 °C, unless otherwise specified



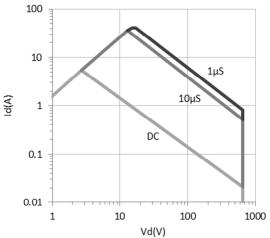


Figure 13. Safe operating Area  $T_C=25~^{\circ}C$ 

(calculated based on thermal limits)

Figure 14. Safe operating Area Tc=80 °C

(calculated based on thermal limits)



#### **Test Circuits and Waveforms**

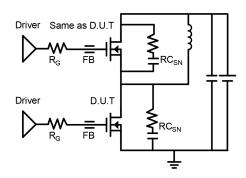


Figure 15. Switching Time Test Circuit

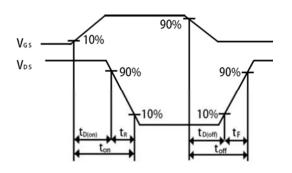


Figure 16. Switching Time Waveform

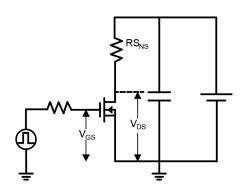


Figure 17. Dynamic  $R_{DS(on)eff}$  Test Circuit

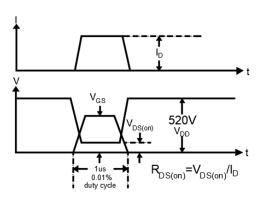


Figure 18. Dynamic  $R_{DS(on)eff}$  Waveform

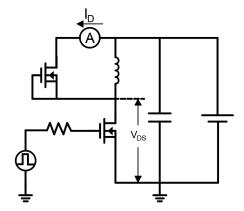


Figure 19. Diode Characteristic Test Circuits

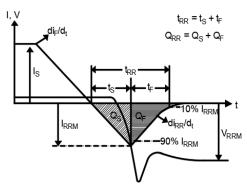


Figure 20. Diode Recovery Waveform



#### **Design Considerations**

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

Before evaluating Runxin Micro's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

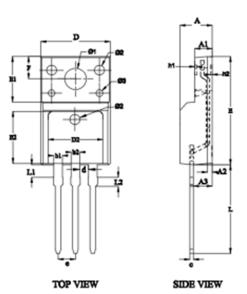
## When Evaluating Runxin Micro's GaN Devices:

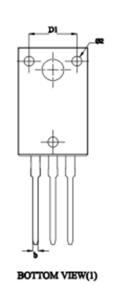
DO	DO NOT
Make sure the traces are as short as possible for both	Using Runxin Micro's devices in GDS board layouts
drive and power loops to minimize parasitic inductance	
Use the test tool with the shortest inductive loop, and	Use differential mode probe or probe ground clip with
make sure test points should be placed close enough	long wires
Minimize the lead length of TO packages when	Use long traces in drive circuit, or long lead length of
installing them to PCB	the devices



#### **Package Outline**

Pin 1: Gate; Pin 2: Source; Pin 3: Drain

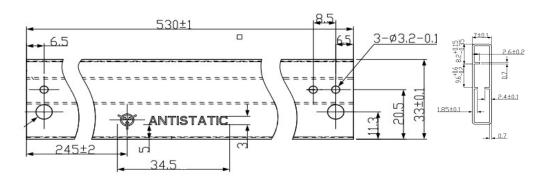




SYMBOL	MILLIMETER		
OT MIDUL	MIN	NOM	MAX
A	4.50	4.74	4.90
A1	2.34	2.58	2.74
A2	0.64	0.74	0.84
A3	2.70	2.80	2.90
b	0.70	0.80	0.92
ъ1/ь2	1.10	—	1.35
c		0.50	
đ	1.20	1.27	1.35
D	9.66	10.16	10.66
D1	6.90	7.00	7.10
D2	7.80	8.00	8.20
E	15.57	15.77	15.97
E1	6.48	6.68	6.88
E2	7.40	7.60	7.80
	:	2.54TY	P
F	3.10	3.30	3.50
h1/h2	0.05	0.10	0.15
L	12.68	12,98	13,28
L1	1.18	1,28	1.38
L2	1.10	1.30	1.50
Ø1	3.18REF		
Ø2	1.50REF		
Ø3	1.00REF		
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#### **Tube Information**

#### Dimensions are shown in millimeters



#### **Revision History**

Version	Date	Change(s)	
0.1	04/10/2023	Release formal datasheet	
0.2	04/21/2023	Revise Rojc,P <sub>D</sub> ,I <sub>D</sub>	